



FINAL PRODUCT/PROCESS CHANGE NOTIFICATION #16867

Generic Copy

Issue Date: 20-Jun-2012

TITLE: Final Notification of Qualification of SP Semiconductor site at Korea for the Assembly and Test of Bipolar Power Transistors in TO-264 package

PROPOSED FIRST SHIP DATE: 20-Sep-2012

AFFECTED CHANGE CATEGORY(S): ON Semiconductor Assembly & Test Site

FOR ANY QUESTIONS CONCERNING THIS NOTIFICATION:

Contact your local ON Semiconductor Sales Office or Jose Ramirez <jose.l.ramirez@onsemi.com>

SAMPLES: Contact your local ON Semiconductor Sales Office or Farrah Awang Omar <farrah.omar@onsemi.com>

ADDITIONAL RELIABILITY DATA: Available

Contact your local ON Semiconductor Sales Office or Laura Rivers <laura.rivers@onsemi.com>

NOTIFICATION TYPE:

Final Product/Process Change Notification (FPCN)

Final change notification sent to customers. FPCNs are issued at least 90 days prior to implementation of the change.

ON Semiconductor will consider this change approved unless specific conditions of acceptance are provided in writing within 30 days of receipt of this notice. To do so, contact <quality@onsemi.com>.

DESCRIPTION AND PURPOSE:

This is to announce the planned capacity expansion of ON Semiconductor assembly and test operations for Bipolar Power Transistors in TO-264 package, currently build at the PSI Manila facility, to SP Semiconductor's Korea facility. Upon the expiration of this FPCN, these devices may be processed at either location. The SP Semiconductor facility is ISO/TS 16949:2002 certified.



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RELIABILITY DATA SUMMARY:

Reliability Test Results:

MJL1302AG

Test:	Conditions:	Interval:	Results
HTRB	Ta=150°C,80% Rated Voltage	1008 hrs	0/80
Autoclave	Ta=121°C RH=100% ~15 psig	96 hrs	0/80
H3TRB	Ta=85°C RH=85% bias=80% rated V or100V Max	1008 hrs	0/80
IOL	Ta=25°C, Delta TJ = 100°C, Ton/off = 2 min.	6000 cycles	0/80
TC	Ta= -65°C to 150°C	1000 cycles	0/80
RSH	Ta=260C, 10 sec dwell		0/30

MJL21193G

Test:	Conditions:	Interval:	Results
HTRB	Ta=150°C,80% Rated Voltage	1008 hrs	0/80
Autoclave	Ta=121°C RH=100% ~15 psig	96 hrs	0/80
H3TRB	Ta=85°C RH=85% bias=80% rated V or100V Max	1008 hrs	0/80
IOL	Ta=25°C, Delta TJ = 100°C, Ton/off = 2 min.	6000 cycles	0/80

MJL21194G

Test:	Conditions:	Interval:	Results
HTRB	Ta=150°C,80% Rated Voltage	1008 hrs	0/80
Autoclave	Ta=121°C RH=100% ~15 psig	96 hrs	0/80
H3TRB	Ta=85°C RH=85% bias=80% rated V or100V Max	1008 hrs	0/80
IOL	Ta=25°C, Delta TJ = 100°C, Ton/off = 2 min.	6000 cycles	0/80

ELECTRICAL CHARACTERISTIC SUMMARY:

There is no change in electrical characteristics. Characterization Data is available upon request.

CHANGED PART IDENTIFICATION:

Product from SP Semiconductor will be identified by SP site code marking.

List of affected General Parts:

MJL4302AG	MJL21195G
MJL4281AG	MJL21194G
MJL3281AG	MJL21193G
MJL21196G	MJL1302AG